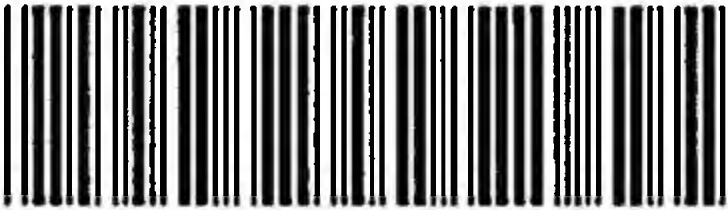


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/710,730	CHEN ET AL.	
	Examiner	Art Unit	
	Evelyn A. Lester	2873	

SEARCHED			
Class	Subclass	Date	Examiner
359	891	12/2/2005	EAL
	707		
	722-724		
	737		
	738	F	↓

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Same As	Above	12/2/2005	EAL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Search: USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB	12/2/2005	EAL